

L Number	Hits	Search Text	DB	Time stamp
1	3712	DFT	USPAT; EPO; JPO; DERWENT	2004/02/23 08:56
2	3712	DFT or (design adj2 for adj2 test)	USPAT; EPO; JPO; DERWENT	2004/02/23 08:57
3	9092	DFT or (design near2 test)	USPAT; EPO; JPO; DERWENT	2004/02/23 08:58
4	5560	design near2 test	USPAT; EPO; JPO; DERWENT	2004/02/23 09:01
5	1058	(reduc\$5 or minimiz\$4) near10 (current near2 surge\$1)	USPAT; EPO; JPO; DERWENT	2004/02/23 09:03
6	714	(reduc\$5 or minimiz\$4) near3 (current near2 surge\$1)	USPAT; EPO; JPO; DERWENT	2004/02/23 09:03
7	141	((reduc\$5 or minimiz\$4) near3 (current near2 surge\$1)) near5 (circuit or device or apparatus)	USPAT; EPO; JPO; DERWENT	2004/02/23 09:04
8	148	((reduc\$5 or minimiz\$4) near3 (current near2 surge\$1)) near5 (circuit or device or apparatus or circuitry)	USPAT; EPO; JPO; DERWENT	2004/02/23 09:16
9	1	((reduc\$5 or minimiz\$4) near3 (current near2 surge\$1)) near5 (circuit or device or apparatus or circuitry) and (IC near2 test\$3)	USPAT; EPO; JPO; DERWENT	2004/02/23 09:05
10	21	((reduc\$5 or minimiz\$4) near3 (current near2 surge\$1)) near5 (circuit or device or apparatus or circuitry) and (test\$3)	USPAT; EPO; JPO; DERWENT	2004/02/23 09:05
11	0	((reduc\$5 or minimiz\$4) near3 (current near2 surge\$1)) near5 (circuit or device or apparatus or circuitry) and (test\$3) and (scan adj2 chain\$2)	USPAT; EPO; JPO; DERWENT	2004/02/23 09:06
12	2	((reduc\$5 or minimiz\$4) near3 (current near2 surge\$1)) near5 (circuit or device or apparatus or circuitry) and (test\$3) and scan\$4	USPAT; EPO; JPO; DERWENT	2004/02/23 09:06
13	43	((reduc\$5 or minimiz\$4) near3 (current near2 surge\$1)) and test\$3 and scan\$4	USPAT; EPO; JPO; DERWENT	2004/02/23 09:07
14	0	((reduc\$5 or minimiz\$4) near3 (current near2 surge\$1)) and (IC near2 test\$3) and scan\$4	USPAT; EPO; JPO; DERWENT	2004/02/23 09:08
15	5	((reduc\$5 or minimiz\$4) near3 (current near2 surge\$1)) and (IC near2 test\$3)	USPAT; EPO; JPO; DERWENT	2004/02/23 09:13
16	0	(current adj3 surge\$1 adj2 minmization adj2 circuitry)	USPAT; EPO; JPO; DERWENT	2004/02/23 09:14
17	0	(current adj3 surge\$1 adj2 minmization)	USPAT; EPO; JPO; DERWENT	2004/02/23 09:14
18	1	(current adj3 surge\$1 adj2 minmization)	USPAT; EPO; JPO; DERWENT	2004/02/23 09:15
19	413	((reduc\$5 or minimiz\$4) near3 (current adj2 surge\$1))	USPAT; EPO; JPO; DERWENT	2004/02/23 09:17
20	329	((reduc\$5 or minimiz\$4) adj3 (current adj2 surge\$1))	USPAT; EPO; JPO; DERWENT	2004/02/23 09:57
21	8	((reduc\$5 or minimiz\$4) near3 (current adj2 surge\$1))) same test\$4	USPAT; EPO; JPO; DERWENT	2004/02/23 09:18
22	0	((reduc\$5 or minimiz\$4) near3 (current adj2 surge\$1))) same (scan adj2 test\$3)	USPAT; EPO; JPO; DERWENT	2004/02/23 09:43

23	8	"current surge circuitry" or "current surge device"	USPAT; EPO; JPO; DERWENT	2004/02/23 09:52
24	1000	"surge arrester" or "current surge circuitry" or "current surge device"	USPAT; EPO; JPO; DERWENT	2004/02/23 09:52
25	1079	"surge arrester" or "current surge circuitry" or "current surge device" or "surge protective device"	USPAT; EPO; JPO; DERWENT	2004/02/23 09:53
26	0	("surge arrester" or "current surge circuitry" or "current surge device" or "surge protective device") same (scan adj2 chain\$2)	USPAT; EPO; JPO; DERWENT	2004/02/23 09:53
27	0	("surge arrester" or "current surge circuitry" or "current surge device" or "surge protective device") and (scan adj2 chain\$2)	USPAT; EPO; JPO; DERWENT	2004/02/23 09:54
28	1	("surge arrester" or "current surge circuitry" or "current surge device" or "surge protective device") and (IC near3 test\$3)	USPAT; EPO; JPO; DERWENT	2004/02/23 09:55
29	136	("surge arrester" or "current surge circuitry" or "current surge device" or "surge protective device") and (test\$3)	USPAT; EPO; JPO; DERWENT	2004/02/23 09:55
30	45	("surge arrester" or "current surge circuitry" or "current surge device" or "surge protective device") same (test\$3)	USPAT; EPO; JPO; DERWENT	2004/02/23 09:56
31	585	((reduc\$5 or minimiz\$4 or limit\$4) adj3 (current adj2 surge\$1))	USPAT; EPO; JPO; DERWENT	2004/02/23 10:00
32	586	((reduc\$5 or minimiz\$4 or limit\$4 or disabl\$4) adj3 (current adj2 surge\$1))	USPAT; EPO; JPO; DERWENT	2004/02/23 10:00
33	586	((reduc\$5 or minimiz\$4 or limit\$4 or disabl\$4 or de-activat\$3) adj3 (current adj2 surge\$1))	USPAT; EPO; JPO; DERWENT	2004/02/23 10:01
34	6	((reduc\$5 or minimiz\$4 or limit\$4 or disabl\$4 or de-activat\$3) adj3 (current adj2 surge\$1)) and (IC near3 test\$3)	USPAT; EPO; JPO; DERWENT	2004/02/23 10:48
35	9	((reduc\$5 or minimiz\$4 or limit\$4 or disabl\$4 or de-activat\$3) near3 (current adj2 surge\$1)) and (IC near3 test\$3)	USPAT; EPO; JPO; DERWENT	2004/02/23 10:08
36	20	((reduc\$5 or minimiz\$4 or limit\$4 or disabl\$4 or de-activat\$3) near3 (current adj2 surge\$1)) and ((IC near3 test\$3) or (test\$3 near3 chip\$1) or (test\$3 near3 (integrated adj2 circuit)))	USPAT; EPO; JPO; DERWENT	2004/02/23 10:36
37	389	parker-k\$.in.	USPAT; EPO; JPO; DERWENT	2004/02/23 10:37
38	3	parker-k\$.in.and ((current adj2 surge\$1) or (IC adj2 testing))	USPAT; EPO; JPO; DERWENT	2004/02/23 10:40
39	30	parker-k\$.in.and ((scan adj2 chain\$1) or (scan adj2 cell\$1) or (scan adj2 test\$3))	USPAT; EPO; JPO; DERWENT	2004/02/23 10:47
40	1	parker-k\$.in.and ((reduc\$5 or minimiz\$4) near10 (current near2 surge\$1))	USPAT; EPO; JPO; DERWENT	2004/02/23 10:47
41	0	((reduc\$5 or minimiz\$4 or limit\$4 or disabl\$4 or de-activat\$3) adj3 (current adj2 surge\$1)) and parker-k\$.in.	USPAT; EPO; JPO; DERWENT	2004/02/23 10:48
42	145	(reduc\$5 or minimiz\$4 or limit\$4 or disabl\$4 or de-activat\$3) and parker-k\$.in.	USPAT; EPO; JPO; DERWENT	2004/02/23 10:49
43	13	((reduc\$5 or minimiz\$4 or limit\$4 or disabl\$4 or de-activat\$3) near3 current) and parker-k\$.in.	USPAT; EPO; JPO; DERWENT	2004/02/23 11:01
44	4627	((reduc\$5 or minimiz\$4 or limit\$4 or disabl\$4 or de-activat\$3) near3 surge)	USPAT; EPO; JPO; DERWENT	2004/02/23 11:02

45	104	((reduc\$5 or minimiz\$4 or limit\$4 or disabl\$4 or de-activat\$3) near3 surge) same test\$3	USPAT; EPO; JPO; DERWENT	2004/02/23 11:02
46	684	((reduc\$5 or minimiz\$4 or limit\$4 or disabl\$4 or de-activat\$3) near3 ("surge current"))	USPAT; EPO; JPO; DERWENT	2004/02/23 11:03
47	90	((reduc\$5 or minimiz\$4 or limit\$4 or disabl\$4 or de-activat\$3) near3 ("surge current")) and test\$3	USPAT; EPO; JPO; DERWENT	2004/02/23 11:03
48	7	((reduc\$5 or minimiz\$4 or limit\$4 or disabl\$4 or de-activat\$3) near3 ("surge current")) same test\$3	USPAT; EPO; JPO; DERWENT	2004/02/23 11:03